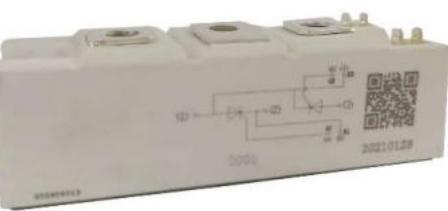


## Description:

- 1) A package of series of two chips.
- 2) With high thermal conductivity DBC as the insulation.
- 3) Welding by vacuum welding technology, which provide high reliability.



## Typical Application:

DC motor control, temperature control and light control system.

**Absolute Maximum Ratings** (Packaged into modules, unless otherwise specified,  $T_{CASE}=25^{\circ}\text{C}$ )

Parameter	Test Conditions	Symbol	Values		Unit
			20	22	
Operating junction temperature range		$T_j$	-40~125		°C
Storage temperature range		$T_{stg}$	-40~125		°C
Repetitive peak off-state voltage	$T_j=25^{\circ}\text{C}$	$V_{DRM}$	2000	2200	V
Repetitive peak reverse voltage	$T_j=25^{\circ}\text{C}$	$V_{RRM}$	2000	2200	V
Non-repetitive peak off-state voltage	$T_j=25^{\circ}\text{C}$	$V_{DSM}$	2100	2300	V
Non-repetitive peak reverse voltage	$T_j=25^{\circ}\text{C}$	$V_{RSM}$	2100	2300	V
Average on-state current	$T_c=85^{\circ}\text{C}$	$I_{T(AV)}/I_{F(AV)}$	200		A
Peak on-state surge current	$t_p=10\text{ms } V_R=0.6V_{RRM}$	$I_{TSM}/I_{FSM}$	5400		A
$I^2t$ value for fusing	$t_p=10\text{ms } V_R=0.6V_{RRM}$	$I^2t$	145000		$\text{A}^2\text{s}$
Critical rate of rise of on-state current	$I_G=2 \times I_{GT}$	$dI/dt$	150		$\text{A}/\mu\text{s}$
Insulation voltage	A.C 50Hz(1s/1min)	$V_{ISO}$	3600/3000		V

**Electrical Characteristics** (Packaged into modules, unless otherwise specified,  $T_{CASE}=25^\circ\text{C}$ )

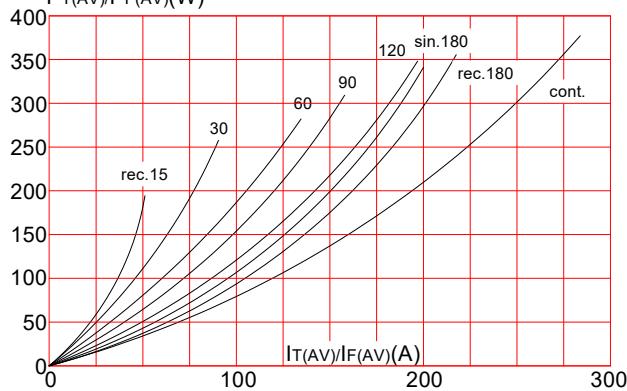
Parameter	Test Conditions	Symbol	Values	Unit
Peak on-state voltage	$I_T=600\text{A}$ $t_P=380\mu\text{s}$	$V_{TM}$	$\leq 1.8$	V
Threshold voltage	$T_j=125^\circ\text{C}$	$V_{TO}$	$\leq 0.9$	V
Dynamic resistance	$T_j=125^\circ\text{C}$	$R_d$	$\leq 1.6$	$\text{m}\Omega$
Repetitive peak off-state current	$V_D=V_{DRM}$ $T_c=25^\circ\text{C}$ $T_c=125^\circ\text{C}$	$I_{DRM1}$ $I_{DRM2}$	$\leq 100$ $\leq 60$	$\mu\text{A}$ $\text{mA}$
Repetitive peak reverse current	$V_R=V_{RRM}$ $T_c=25^\circ\text{C}$ $T_c=125^\circ\text{C}$	$I_{RRM1}$ $I_{RRM2}$	$\leq 100$ $\leq 60$	$\mu\text{A}$ $\text{mA}$
Triggering gate current	$V_D=12\text{V}$ $R_L=30\Omega$	$I_{GT}$	20-120	mA
Holding current	$I_T=1\text{A}$	$I_H$	$\leq 250$	mA
Latching current	$I_G=1.2 I_{GT}$	$I_L$	$\leq 300$	mA
Triggering gate voltage	$V_D=12\text{V}$ $R_L=30\Omega$	$V_{GT}$	$\leq 1.8$	V
Non triggering gate voltage	$V_D=V_{DRM}$ $T_j=125^\circ\text{C}$	$V_{GD}$	$\geq 0.25$	V
Critical rate of rise of voltage	$V_D=2/3V_{DRM}$ $T_j=125^\circ\text{C}$ Gate Open	$dv/dt$	$\geq 1000$	$\text{V}/\mu\text{s}$
Thermal resistance	Junction to case Case to heatsink	$R_{th(j-c)}$ $R_{th(c-s)}$	0.12 0.08	$^\circ\text{C}/\text{W}$

## Mechanical Characteristics

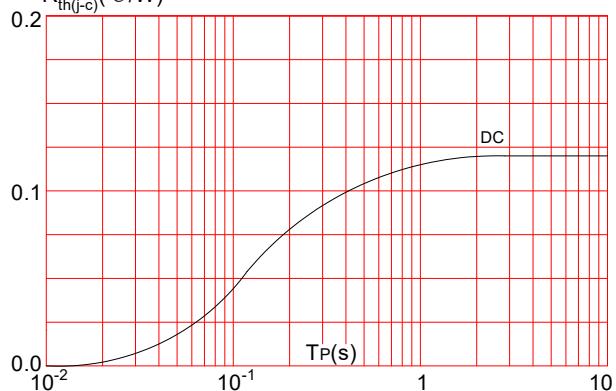
Module size	94mm×34.2mm
Module height	29.5mm
Terminal distance of (1) /(2) /(3)	23mm
Mounting torque(M5)	5±15%Nm
Terminal torque(M6)	5±15%Nm
 T2	 AKMD symbol  AKMH symbol

## Performance Curves

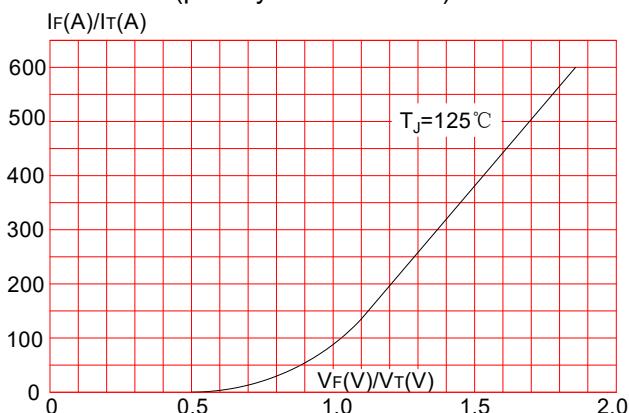
**FIG.1:** Power dissipation vs. on-state current (per thyristor or diode)  
 $P_{T(AV)}/P_{F(AV)}(W)$



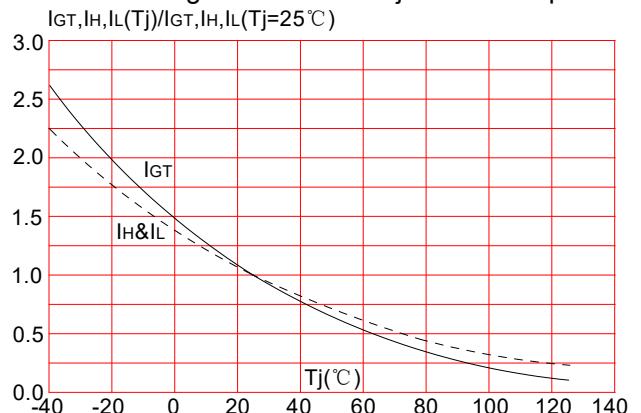
**FIG.2:** Maximum transient thermal impedance junction to case(per thyristor or diode)  
 $R_{th(j-c)}(^\circ C/W)$



**FIG.3:**Forward characteristics  
(per thyristor or diode)



**FIG.4:** Relative variations of gate trigger current, holding current and latching current versus junction temperature



### Ordering Information

Aiko Electronics Technology Co., LTD

AK

MD

200 / 22

20:  $V_{DRM}/V_{RRM} \geq 2000V$   
22:  $V_{DRM}/V_{RRM} \geq 2200V$

MD: Thyristor module

MH: Thyristor and diode module

$I_{T(AV)}/I_{F(AV)} = 200A$